

MCR16NG





Description

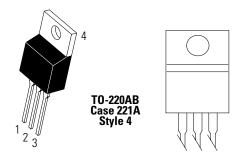
Designed primarily for half-wave ac control applications, such as motor controls, heating controls, and power supplies; or wherever half-wave, silicon gate-controlled devices are needed.

Features

- Blocking Voltage to 800 Volts
- On–State Current Rating of 16 Amperes RMS
- High Surge Current Capability – 160 Amperes
- Rugged Economical TO-220AB Package
- Glass Passivated Junctions for Reliability and Uniformity
- Minimum and Maximum Values of IGT, VGT, and IH Specified for Ease of Design
- High Immunity to dv/dt

 100 V/sec Minimum at
 125°C
- These are Pb–Free Devices

Pin Out



Functional Diagram



Additional Information







Thyristors Surface Mount - 800V > MCR16NG

Maximum Ratings (T _J = 25°C unless otherwise noted)						
Rating		Symbol	Value	Unit		
Peak Repetitive Off–State Voltage (Note 1) (– 40 to 125°C, Sine Wave, 50 to 60 Hz, Gate Open)	MCR8SDG	V _{DRM} , V _{RRM}	800	V		
On-State RMS Current (180° Conduction Angles; T _C = 80°C)		I _{T (RMS)}	16	А		
Peak Non-Repetitive Surge Current (1/2 Cycle, Sine Wave 60 Hz, T _J = 125°C)		I _{TSM}	160	А		
Circuit Fusing Consideration (t = 8.3 ms)		l²t	106	A²sec		
Forward Peak Gate Power (Pulse Width ≤ 1.0 µsec, T _C = 80°C)		P _{GM}	5.0	W		
Forward Average Gate Power (t = 8.3 msec, T _c = 80°C)		P _{GM (AV)}	0.5	W		
Forward Peak Gate Current (Pulse Width ≤ 1.0 µsec, T _c = 80°C)		I _{GM}	2.0	А		
Operating Junction Temperature Range		T _J	-40 to 125	°C		
Storage Temperature Range		T _{sta}	-40 to 150	°C		

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is

Thermal Characteristics

Rati	ng	Symbol	Value	Unit
Thermal Resistance	Junction-to-Case (AC) Junction-to-Ambient	R _{ejc} R _{eja}	1.5 62.5	°C/W
Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 10 seconds		T _L	260	°C

Electrical Characteristics - OFF (T_c = 25°C unless otherwise noted)

Characteristic		Symbol	Min	Тур	Max	Unit
†Peak Repetitive Blocking Current	T ₁ = 25°C	I _{DRM} ,	-	-	0.01	μΑ
$(V_{AK} = V_{DRM} = V_{RRM}; Gate Open)$	T _J = 125°C	I	-	-	2.0	mA

Electrical Characteristics - ON (T_J = 25°C unless otherwise noted; Electricals apply in both directions)

Characteristic		Min	Тур	Max	Unit
Peak Forward On-State Voltage (Note 2) (I _{TM} = 32 A)	V _{TM}	_	_	1.7	V
Gate Trigger Current (Continuous dc) $(V_D = 12 \text{ V}; R_L = 100 \Omega)$		2.0	10	20	mA
Holding Current (Anode Voltage = 12 V, Initiating Current = 200 mA)		4.0	25	40	mA
Latch Current (V _D = 12 V, I _G = 200 mA)		_	30	60	mA
Gate Trigger Voltage (Continuous dc) ($V_D = 12 \text{ V}, R_L = 100 \Omega$)		0.5	0.65	1.0	V

Dynamic Characteristics

Characteristic	Symbol	Min	Тур	Max	Unit
Critical Rate of Rise of Off–State Voltage $(V_D = Rated V_{DRM'} Exponential Waveform, Gate Open, T_J = 125°C)$	dv/dt	100	300	_	V/µs
Critical Rate of Rise of On–State Current ($I_{PK} = 50 \text{ A}$, $PW = 30 \mu \text{sec}$, $diG/dt = 1 \text{ A/} \mu \text{sec}$, $lgt = 50 \text{ mA}$	di/dt	-	_	50	A/μs

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

1. V_{DRM} and V_{RRM} for all types can be applied on a continuous basis. Ratings apply for zero or negative gate voltage; however, positive gate voltage shall not be applied concurrent with negative potential on the anode. Blocking voltages shall not be tested with a constant current source such that the voltage ratings of the devices are exceeded.

^{2.} Pulse Test; Pulse Width ≤ 2.0 msec, Duty Cycle ≤ 2%.



Voltage Current Characteristic of SCR

Symbol	Parameter
V_{DRM}	Peak Repetitive Forward Off State Voltage
I _{DRM}	Peak Forward Blocking Current
V _{RRM}	Peak Repetitive Reverse Off State Voltage
I _{RRM}	Peak Reverse Blocking Current
V _{TM}	Maximum On State Voltage
I _H	Holding Current

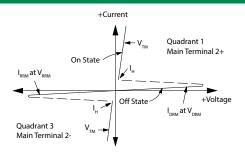


Figure 1. Typical RMS Current Derating

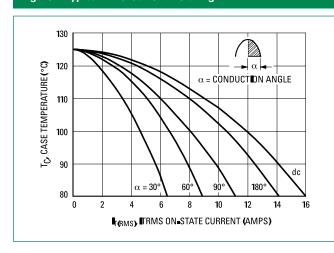


Figure 2. On-State Power Dissipation

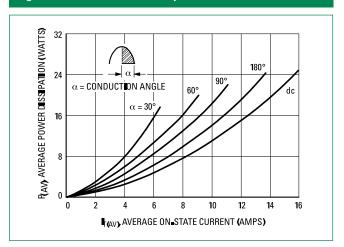


Figure 3. Transient Thermal Response

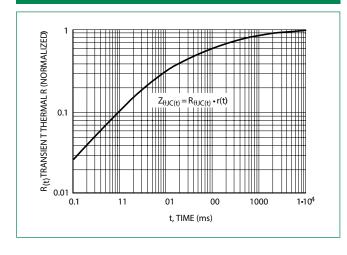


Figure 4. Typical Holding Current vs Junction Temperature

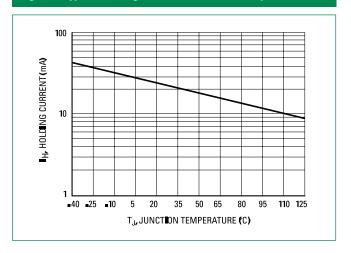




Figure 5. Typical On-State Characteristics

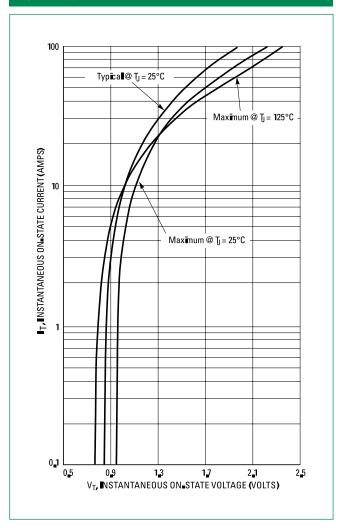


Figure 6. Typical Latching Current vs Junction Temperature

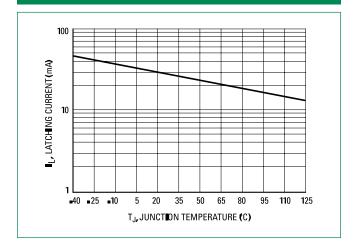


Figure 7 Typical Gate Trigger Current vs Junction Temperature

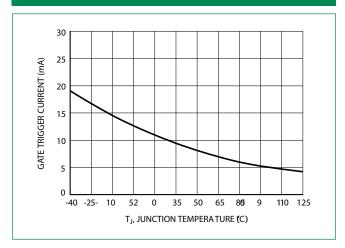


Figure 8. Typical Gate Trigger Voltage vs Junction Temperature

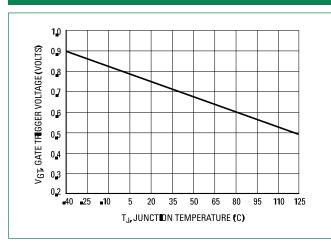
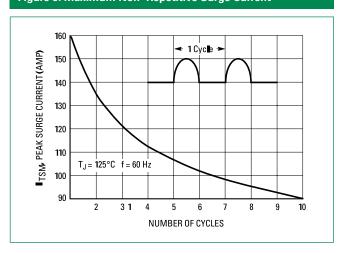
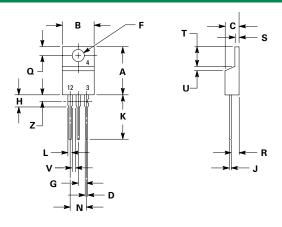


Figure 9. Maximum Non-Repetitive Surge Current

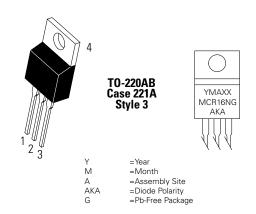




Dimensions



Part Marking System



D:	Inches		Millin	neters	
Dim	Min	Max	Min	Max	
Α	0.590	0.620	14.99	15.75	
В	0.380	0.420	9.65	10.67	
С	0.178	0.188	4.52	4.78	
D	0.025	0.035	0.64	0.89	
F	0.142	0.147	3.61	3.73	
G	0.095	0.105	2.41	2.67	
Н	0.110	0.130	2.79	3.30	
J	0.018	0.024	0.46	0.61	
K	0.540	0.575	13.72	14.61	
L	0.060	0.075	1.52	1.91	
N	0.195	0.205	4.95	5.21	
Q	0.105	0.115	2.67	2.92	
R	0.085	0.095	2.16	2.41	
S	0.045	0.060	1.14	1.52	
Т	0.235	0.255	5.97	6.47	
U	0.000	0.050	0.00	1.27	
V	0.045		1.15		
Z		0.080	-	2.04	

Pin Assignment				
1 Cathode				
2	Anode			
3	Gate			
4	Anode			

Ordering Information						
Device	Package	Shipping				
MCR16NG	TO-220AB (Pb-Free)	500 Units / Box				

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- 2. CONTROLLING DIMENSION: INCH.
 3. DIMENSION Z DEFINES A ZONE WHERE ALL BODY AND LEAD IRREGULARITIES ARE